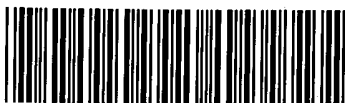


Search Notes



Application No.

09/583,617

Examiner

Bernard E Souw

Applicant(s)

GORUGANTHU ET AL.

Art Unit

2881

SEARCHED

Class	Subclass	Date	Examiner
250	306,307	03/68-	
	310,311	04/03-	
	752.3	-27	BES
	492.2	2004	
	492.22		
<i>Updated</i>			
		04/27/04	BES

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
<i>[induced with (failures or defects)]</i>		
<i>(electron near beam)</i>	03/08	BES
<i>with (suspect of near semiconductor)</i>	↓	↓
<i>and/induced with (failure or defect)</i>	04/27/04	BES
<i>+ durability test</i>		